

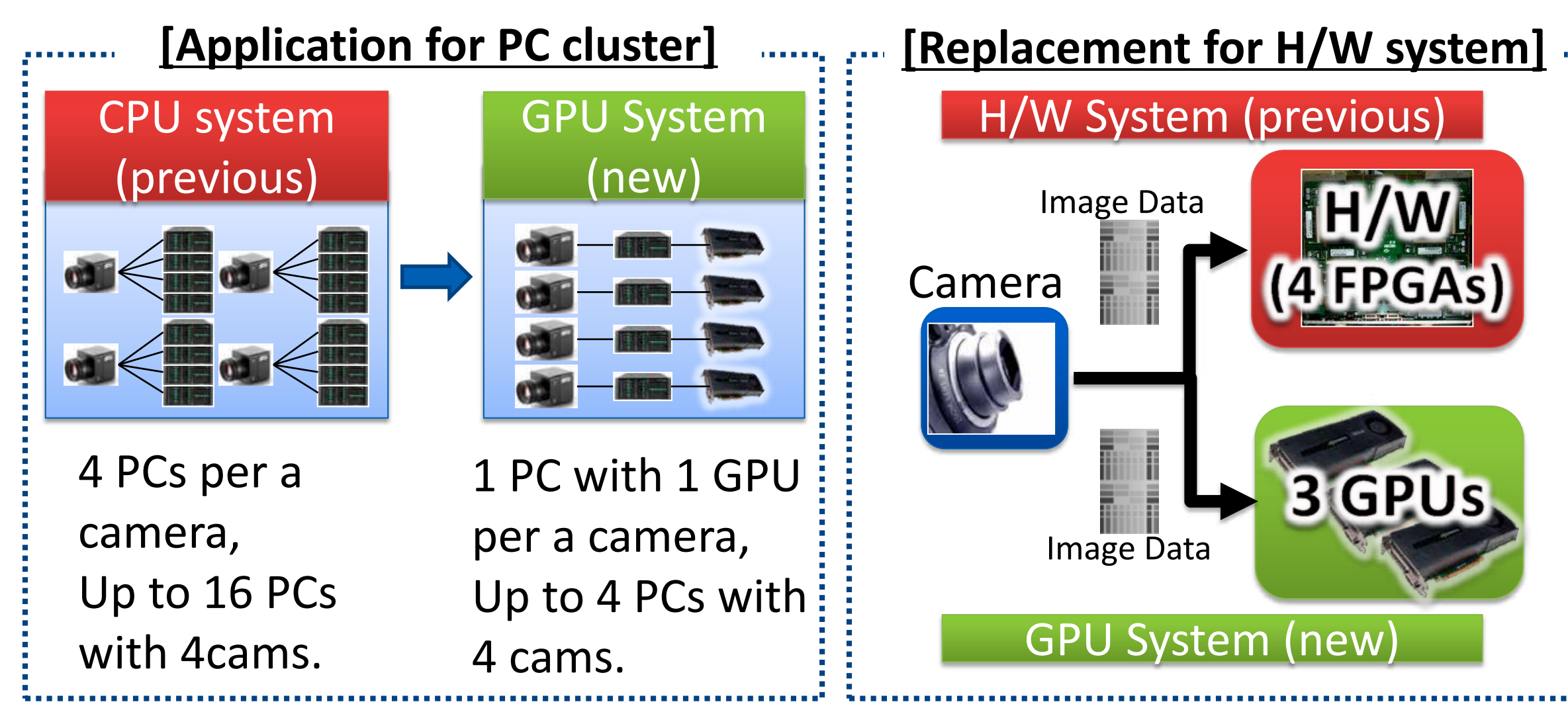


Input Resource Reduction in Development for Industrial Measurement Systems, using GPUs

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1. Abstract

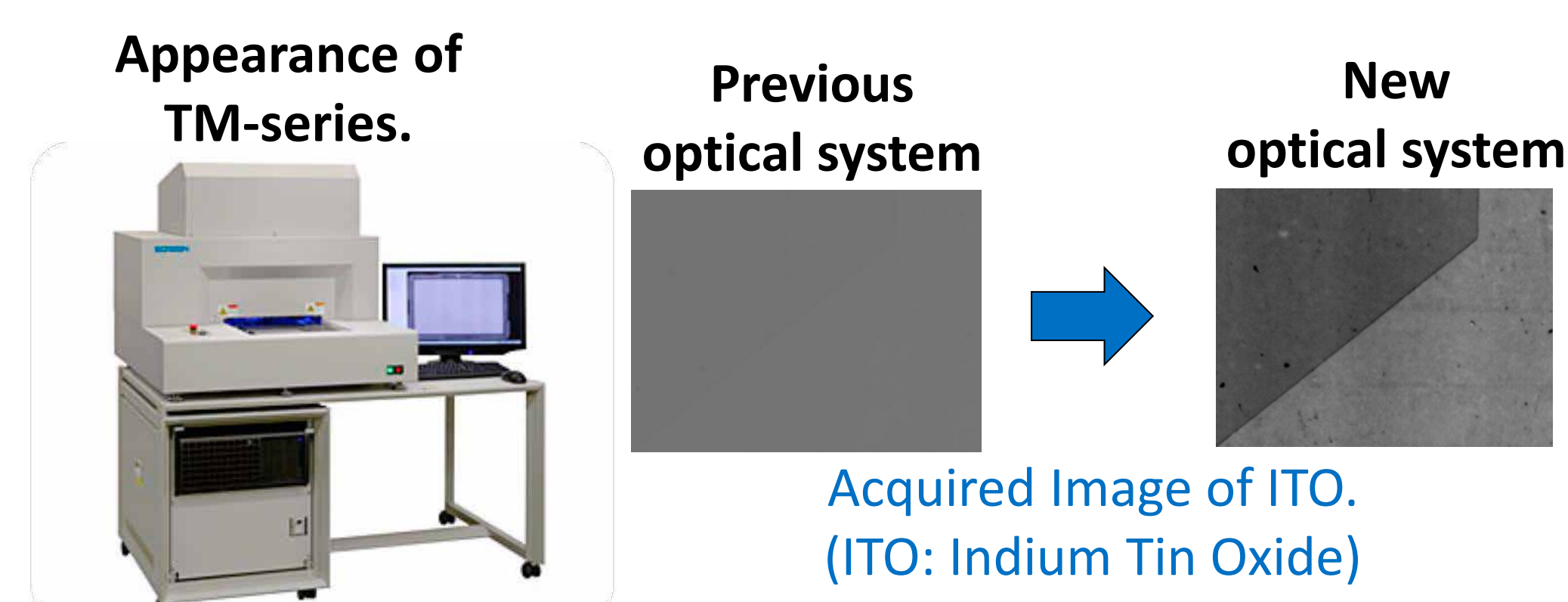
- Industrial inspection/measurement systems, our products, handle large volume data such as very high resolution images over GB size. And, they must inspect/measure these data with rapidity.
- As a solutions, we have been applying GPUs to our existing systems in the figure below, and reduced input resource in development.
- We present a new case of application development process.



2. Application

2.1 Transparent Electrode Monitor

- A monitoring system processes optical images of specimen surface acquired with cameras.
- Our Transparent Electrode monitor "TM-series" targets transparent electrodes equipped touch panel devices, such as smartphones and tablet PCs.
- "TM-series" acquire the transparent electrode images to measure widths in their conductor line patterns.



2.2 Motivation & Goal

[Motivation]

- User needs requires quick response through flexible and continuous development of algorithms.
- But the conventional FPGA-based H/W does not respond with enough flexibility and rapidity in development.
- Therefore we develop on GPUs.

[Goal]

- To develop the algorithms concurrently with the whole development including mechanical, electrical, and optical process and so on.
- To reduce the input resource in development for flexibility and rapidity.
- To achieve the performance to measure a large image (max:23GB) within 70 seconds with the GPU system.

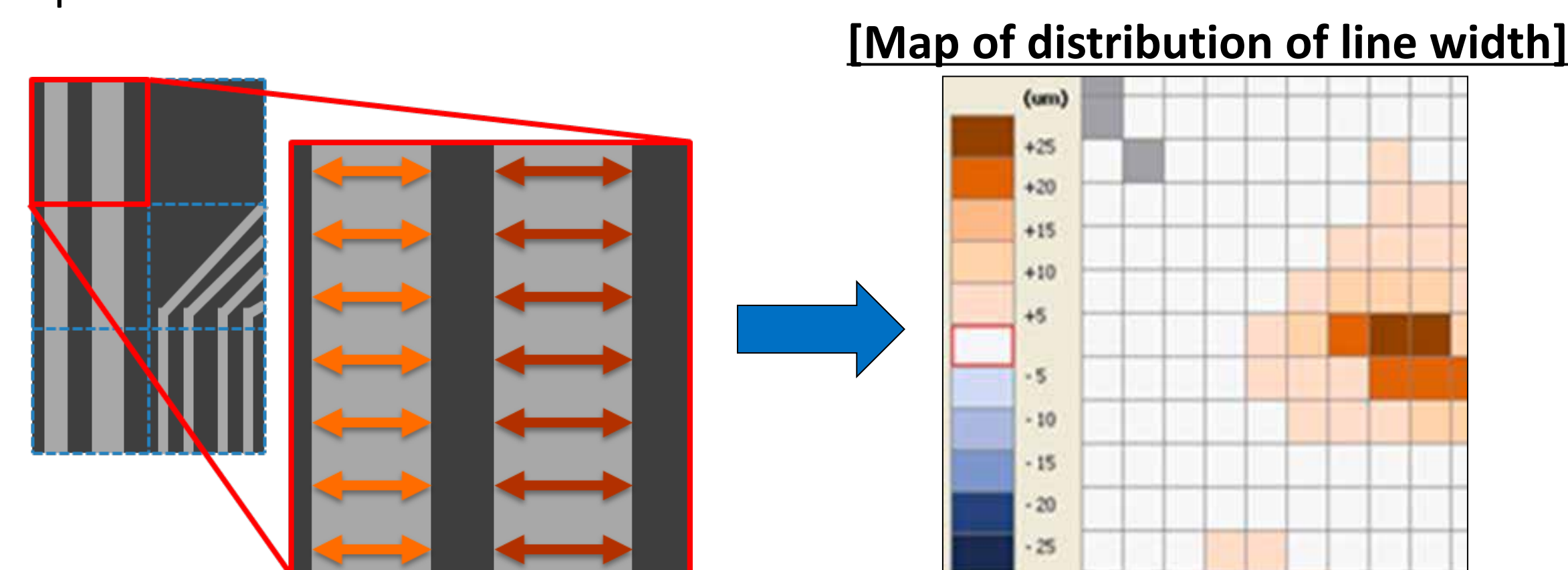
3. Details of Development

3.1 Basic Image Processing

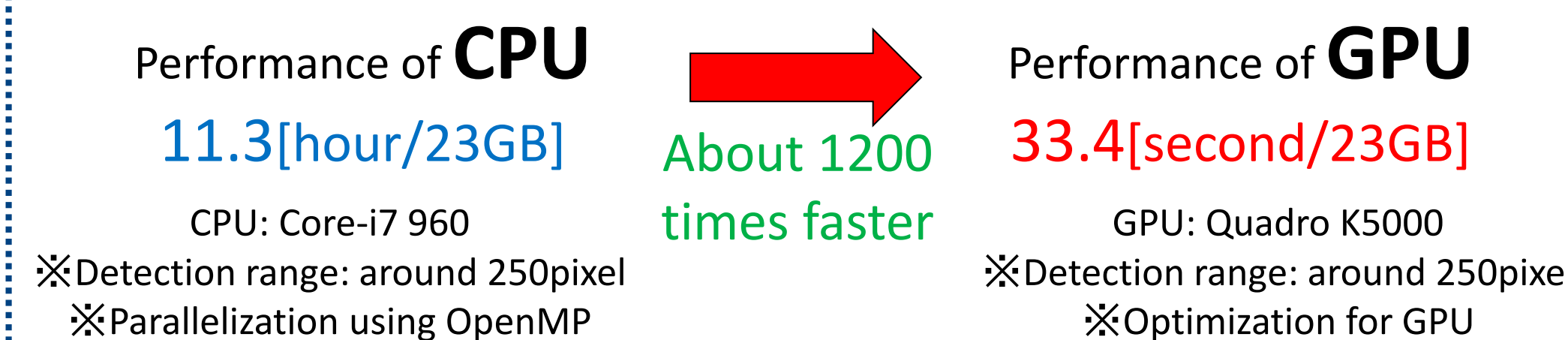
- The following methods is developed with GPU.
 - Luminance correction
 - Distortion correction
 - Enhancement of contrast ...etc.

3.2 Measurement the Distribution of Width in Conductor Line

- This system measures widths in conductor line of the whole film, and make a map of line width distribution (thin/bold) for each area.
- The map is used for a rough error check of the transparent electrode.
- Because the detection range is over 100 pixels, high performance method is required.

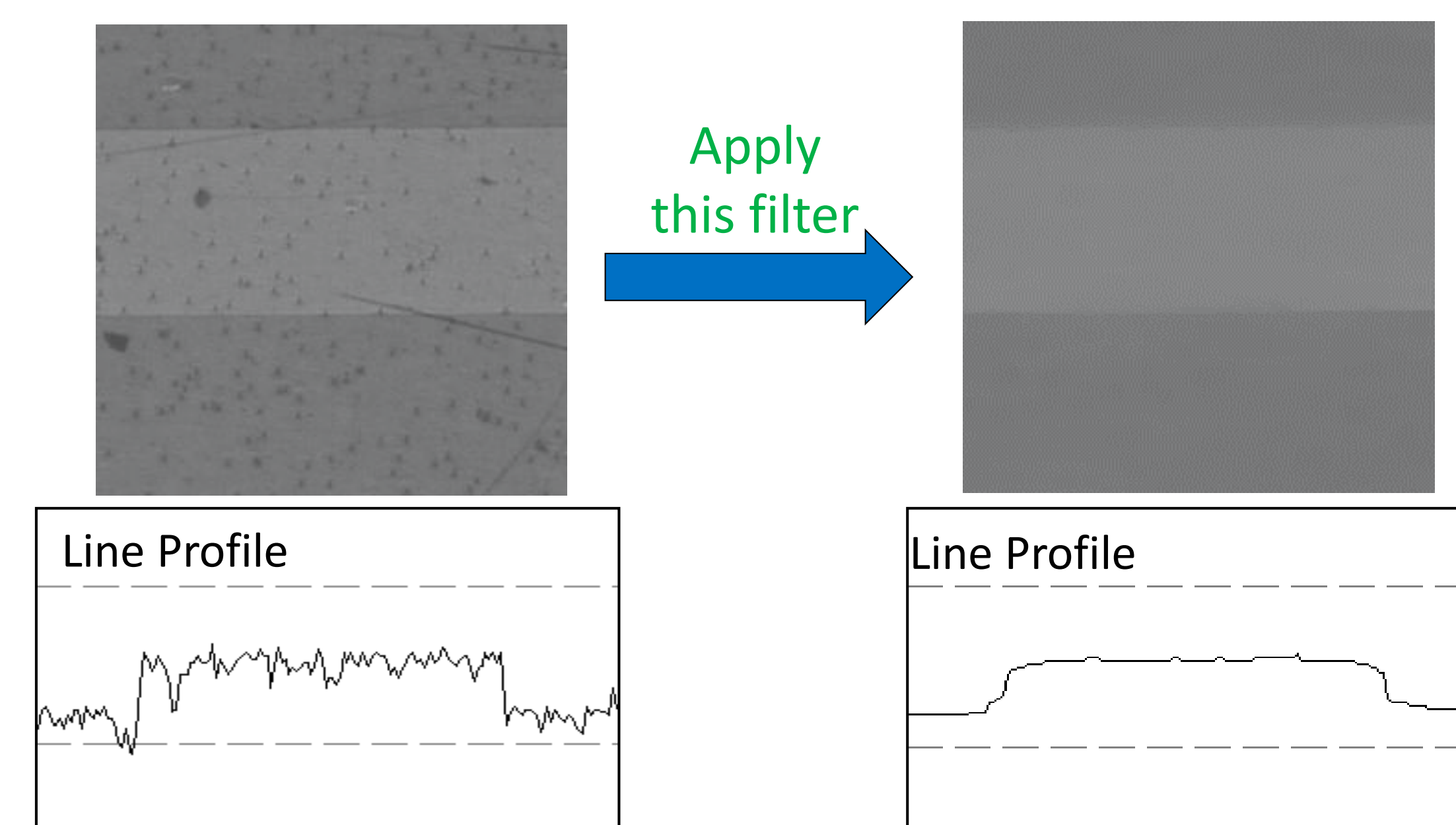


[An Example of performance evaluation]

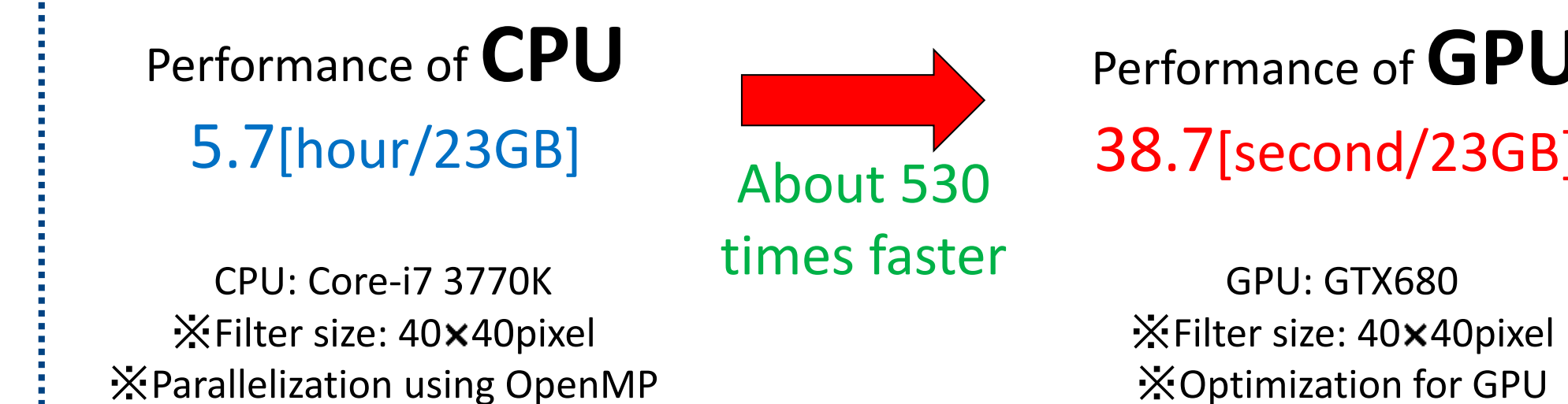


3.3 Filter to Remove the Particulate Elements

- An original filter algorithm was required to remove the particulate elements in the image while keeping edge of transparent electrode.
- The cause of particulate elements includes filler, rough surface of films and measurement noise.
- A high performance method is required to apply the filter based on a bilateral filter with notoriously very large calculation volume.



[An Example of performance evaluation]



4. Resource Reduction Result

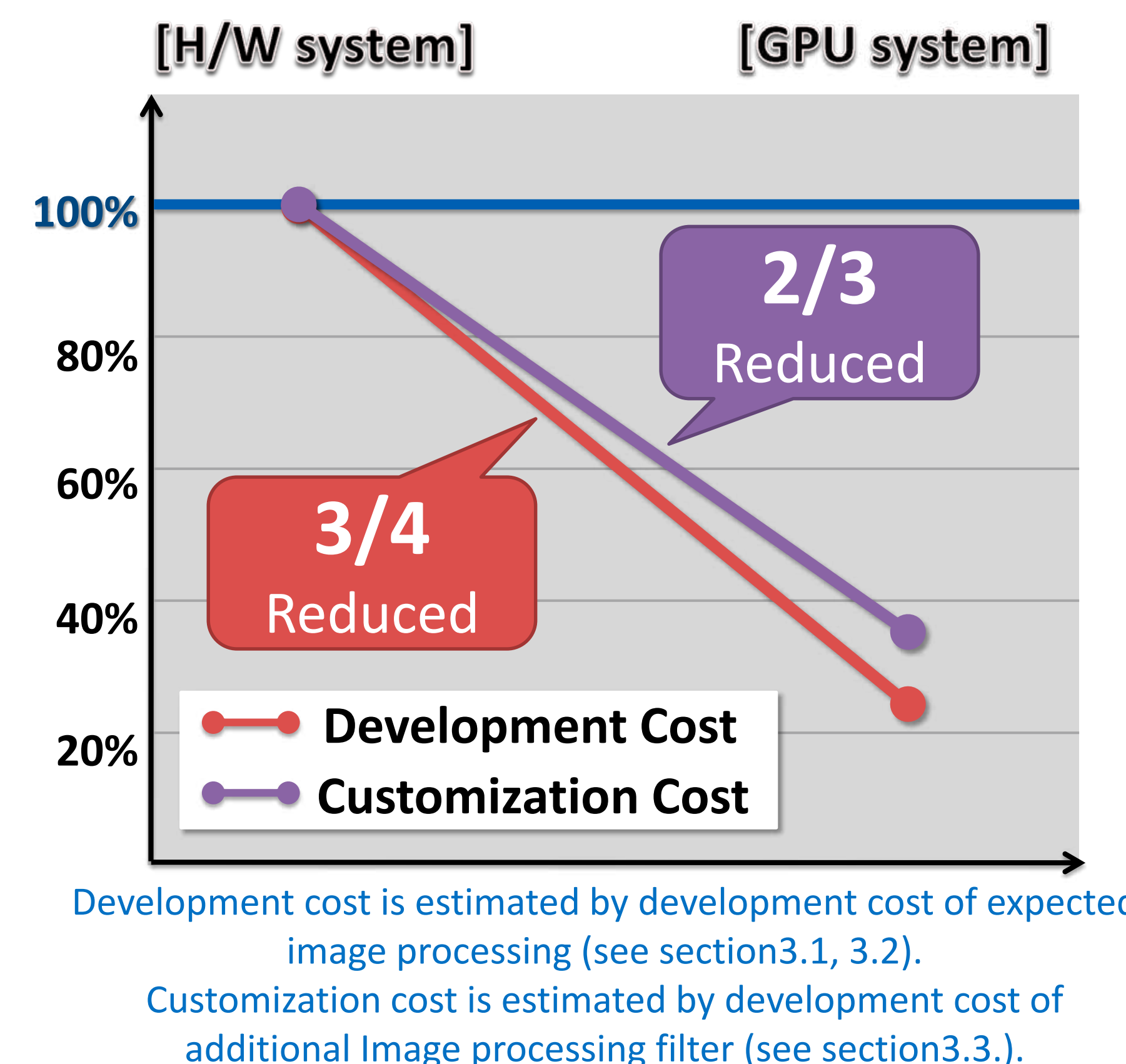
- The reduction of input resource - human resource and development period - is estimated by comparison with the conventional development on FPGA-based H/W.

[Development Cost]

- Utilizing the GPU has reduced image processing development cost by 3/4 enabling quick response to user needs.

[Customization Cost]

- The flexible development process utilizing the GPU has lowered image processing customization cost by 2/3 even handling unexpected problems.



5. Summary

- We have demonstrated a result of input resource reduction in development process with GPUs through an actual application in a monitoring system for the transparent electrode.
- Development process with GPUs has reduced development cost by 3/4 and customization cost by 2/3 compared to one with FPGA-Based H/W system.
- This system has attained expected performance.
- This result proves effectiveness in acceleration of development process with GPUs for the industrial inspection/measurement systems.
- We will keep applying GPUs to new applications in various ways.